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(71) Applicant (for all designated States except US):
ACANOVA AB [SE/SE]; Ulls väg 30A, Box 810,
S-751 08 Uppsala (SE).

(72) Inventors; and

(75) Inventors/Applicants (for US only): ENGQVIST,

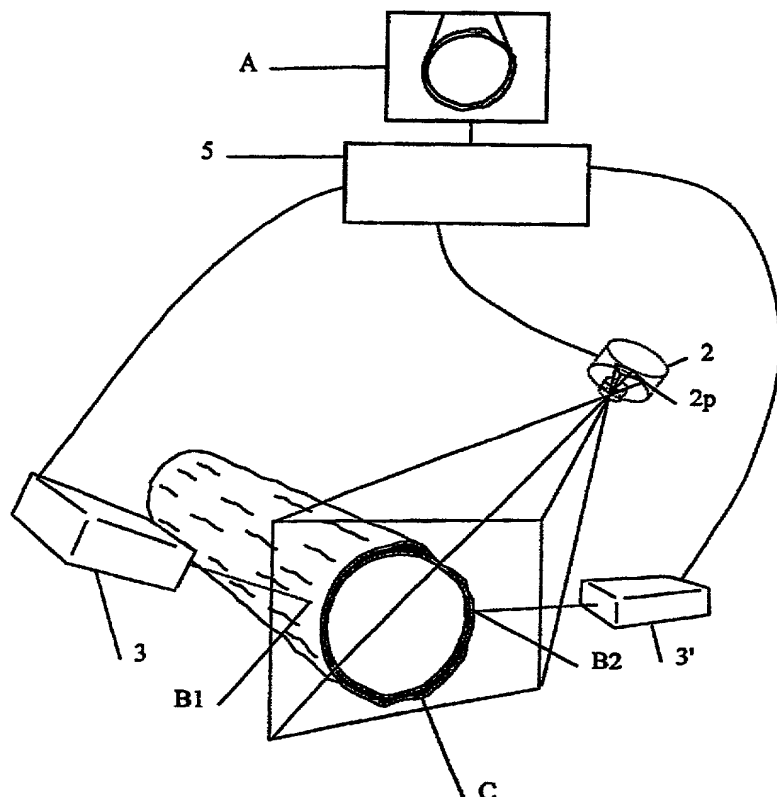
Anders [SE/SE]; Våktargatan 42B, S-754 22 Uppsala (SE). WRETBLAD, Per [SE/SE]; Börje Bösslinge, S-755 92 Uppsala (SE). ANDERSSON, Sven [SE/SE]; Fahlströms väg 8, S-741 92 Uppsala (SE). NYLINDER, Mats [SE/SE]; Dalbovägen 41A, S-756 53 Uppsala (SE). ALNESS, Kenneth [SE/SE]; Östuna Täby, S-751 94 Knivsta (SE).

(74) Agents: JOHANSSON, Roger et al.; Uppsala Patentbyrå AB, Box 9013, S-750 09 Uppsala (SE).

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(54) Title: METHOD AND DEVICE FOR LOG MEASUREMENT



(57) Abstract: The invention refers to a method, and a device, to be used in sorting plant for saw timber in order to measure the dimension, profile and other properties of individual logs and thereby improving the sawyield. The method comprises an image analysis system and at least one further measuring system, which are used to determine the wood surface profile under the bark of the log end, whereby the wood surface profile, obtained with the image analysis, is combined with another wood surface profile, obtained with another measuring technique, or the image analysis utilizes measurement results obtained from another measurement to determine the wood surface profile.